# **Power MOSFET**

# 30 V, 59 A, Single N-Channel, SO-8FL

## **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Low RG
- These are Pb-Free Devices

#### **Applications**

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters

## **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise stated)

	, ,			,	
Para	Parameter			Value	Unit
Drain-to-Source Volta	age		$V_{DSS}$	30	V
Gate-to-Source Volta	age		$V_{GS}$	±20	V
Continuous Drain Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	13.5 9.7	А
Power Dissipation R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	2.16 1.1	W
Continuous Drain Current R <sub>θJA</sub> ≤10 s		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	21.8 15.7	A
Power Dissipation $R_{\theta JA} \leq 10 \text{ s}$	Steady State	T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	5.7 2.9	W
Continuous Drain Current R <sub>0JA</sub> (Note 2)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	8.6 6.2	А
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	0.87 0.45	W
Continuous Drain Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C T <sub>C</sub> = 85°C	I <sub>D</sub>	59 42.5	А
Power Dissipation R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C T <sub>C</sub> = 85°C	P <sub>D</sub>	41.7 21.7	W
Pulsed Drain Current	t <sub>p</sub> = 10 μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	177	Α
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C	
Source Current (Body Diode)		I <sub>S</sub>	35	Α	
Drain to Source dV/dt		dV/dt	6	V/ns	
Single Pulse Drain–to–Source Avalanche Energy (V <sub>DD</sub> = 24 V, V <sub>GS</sub> = 10 V, I <sub>L</sub> = 25.6 A, L = 0.3 mH, R <sub>G</sub> = 25 $\Omega$ )		EAS	98	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

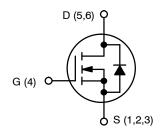
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



## ON Semiconductor®

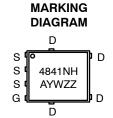
## http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	$6.72~\mathrm{m}\Omega$ @ $10~\mathrm{V}$	50 A
30 V	11.6 mΩ @ 4.5 V	59 A



**N-CHANNEL MOSFET** 





A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

## ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTMFS4841NHT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4841NHT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3	
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	57.8	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	143.5	°C/ <b>VV</b>
Junction–to–Ambient (t≤10 s)	$R_{ heta JA}$	22.1	

## FI FCTRICAL CHARACTERISTICS (T = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS						•	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu A$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				28		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25 °C			1	μΑ
		V <sub>DS</sub> = 24 V	T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	; = ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.5	2.1	2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.6		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V to	I <sub>D</sub> = 30 A		4.8	6.72	- mΩ
		11.5 V	I <sub>D</sub> = 15 A		4.8		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		8.8	11.6	
			I <sub>D</sub> = 15 A		8.5		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 50 A			57		S
CHARGES AND CAPACITANCES	•					1	
Input Capacitance	C <sub>ISS</sub>			939	1565	2113	
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 12 V		195	325	439	pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			103.8	173	242.2	1
Total Gate Charge	Q <sub>G(TOT)</sub>				11.3	15.82	1
Threshold Gate Charge	Q <sub>G(TH)</sub>		45.11 00 A		1.4	2.1	nC
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 3.5 \text{ V}$	15 V; I <sub>D</sub> = 30 A		5.3	7.9	
Gate-to-Drain Charge	$Q_{GD}$				4.5	6.8	
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_D = 30 \text{ A}$			24.4	33	nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t <sub>d(ON)</sub>				12.1	18.1	
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 1	5 V. In = 15 A		23.3	34.9	1
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$R_G = 3.0 \Omega$			14.1	21.1	ns ns
Fall Time	t <sub>f</sub>				4.9	7.3	
Turn-On Delay Time	t <sub>d(ON)</sub>				7.2	10.7	
Rise Time	t <sub>r</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			20.6	30.9	ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				21.9	32.9	
Fall Time	t <sub>f</sub>				2.9	4.4	

- 3. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

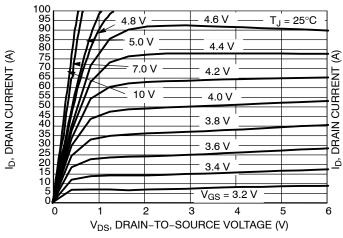
## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit		
DRAIN-SOURCE DIODE CHARACTERISTICS									
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.86	1.2			
		I <sub>S</sub> = 30 A	T <sub>J</sub> = 125°C		0.71		V		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A}/\mu\text{s,}$ $I_{S} = 30 \text{ A}$			18.8				
Charge Time	t <sub>a</sub>				11.4		ns		
Discharge Time	t <sub>b</sub>				7.4				
Reverse Recovery Charge	Q <sub>RR</sub>				6.7	26.7	nC		
PACKAGE PARASITIC VALUES									
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.93		nH		
Drain Inductance	L <sub>D</sub>				0.005				
Gate Inductance	L <sub>G</sub>				1.84				
Gate Resistance	R <sub>G</sub>				0.90		Ω		

<sup>3.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

## **TYPICAL CHARACTERISTICS**

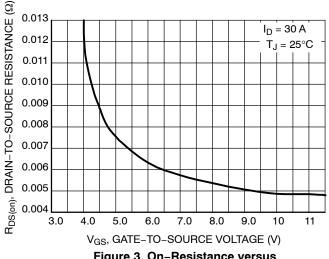
90



80
70
60
50
40  $T_C = 25^{\circ}C$ 10  $T_C = 125^{\circ}C$ 10  $T_C = -55^{\circ}C$ 

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



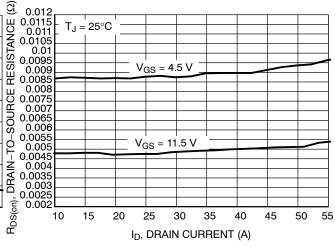
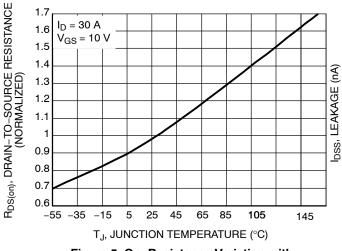


Figure 3. On-Resistance versus Gate-to-Source Voltage

Figure 4. On-Resistance versus Drain Current and Gate Voltage



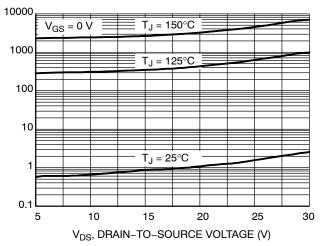
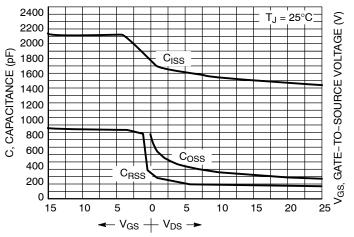


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current versus Voltage

## **TYPICAL CHARACTERISTICS**



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (V)

Figure 7. Capacitance Variation

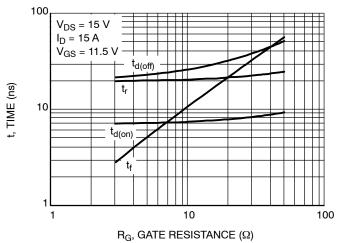


Figure 9. Resistive Switching Time Variation versus Gate Resistance

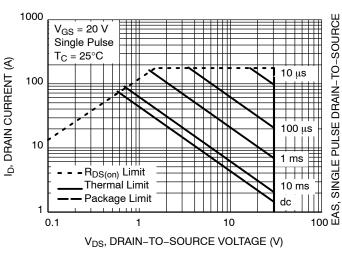


Figure 11. Maximum Rated Forward Biased Safe Operating Area

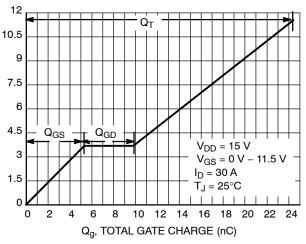


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

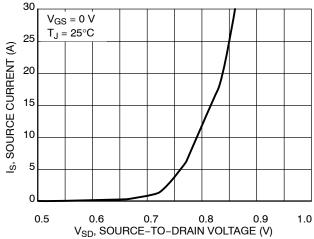


Figure 10. Diode Forward Voltage versus

Current

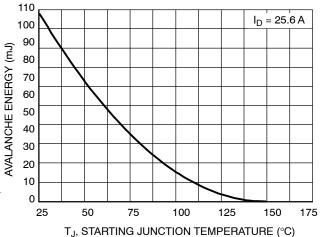


Figure 12. Maximum Avalanche Energy versus Starting Junction Temperature

## **TYPICAL CHARACTERISTICS**

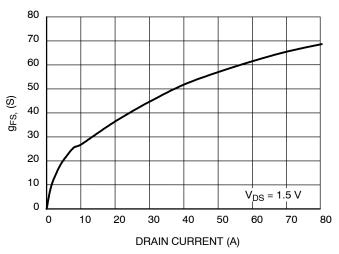


Figure 13. G<sub>FS</sub> versus Drain Current

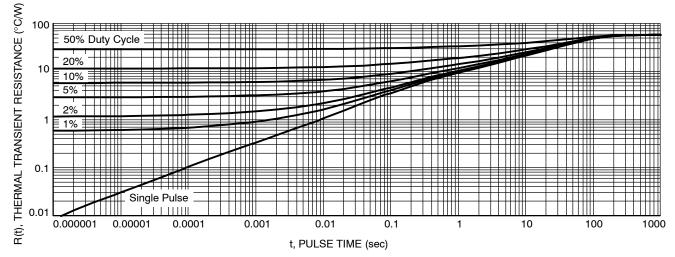
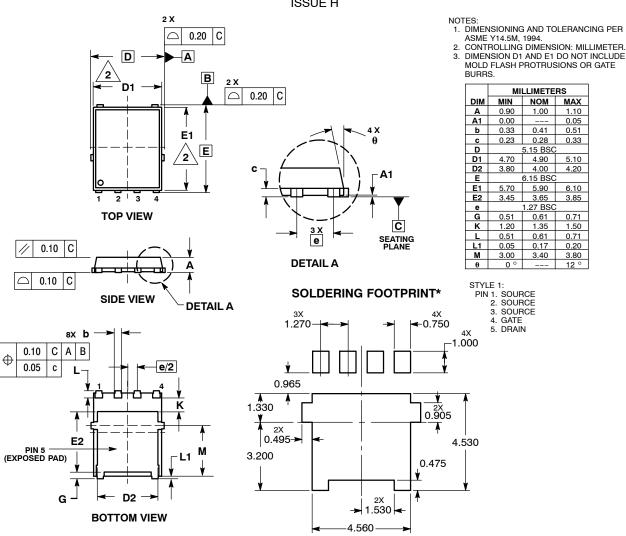


Figure 14. Thermal Resistance

## PACKAGE DIMENSIONS





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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